## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

Susie X. YANG et al.

Serial No. 10/809,908

Filed: March 26, 2004

Group Art Unit: 2125

Examiner: Ryan A. Jarrett

IMPROVED CONTROL OF METAL RESISTANCE IN SEMICONDUCTOR

PRODUCTS VIA INTEGRATED METROLOGY

## **REPLY TO OFFICE ACTION**

Honorable Commissioner for Patents Alexandria, VA 22313-1450

Sir:

For:

This submission is responsive to the Office Action dated June 28, 2005. A petition for a two-month extension of time accompanies this reply to extend the period for response up to and including November 28, 2005.

Amendments to the claims are found starting on page 2 of this paper.

Remarks/Arguments start on page 14 of this paper.